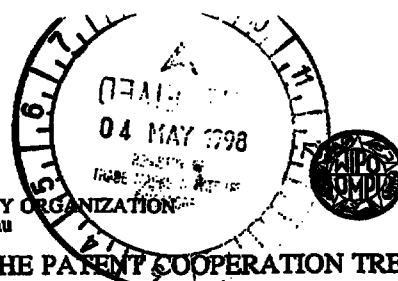


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(54) Title: A NETWORK ANALYSIS SYSTEM (57) Abstract A network analysis system which obtains parameter data generated by equipment of a telecommunications network. The parameter data represents operational parameters of the network. The system processes the parameter data to generate symptom data from test procedures applied to the parameter data. Fault data is generated, which is representative of faults which may have occurred, on the basis of the symptom data and relationship data representative of the relationship between the symptom data and the faults. The relationship between a symptom and a fault represents the likelihood of the system being caused by the fault. The system also generates occurrence data, which is representative of faults which probably have occurred, on the basis of the fault data. <pre> graph TD 10["#"] --> 12[DC] 12 --> 4[Data Store] 4 --> 6[DIN] 6 --> 8[DRES] 8 --> Out[] </pre>		